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(54) **REORDERING OR REMOVAL OF TEST PATTERNS FOR DETECTING FAULTS IN INTEGRATED CIRCUIT**

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(52) **U.S. Cl.**

CPC .. ***G01R 31/318547*** (2013.01); ***G01R 31/31835*** (2013.01)

(58) **Field of Classification Search**

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See application file for complete search history.

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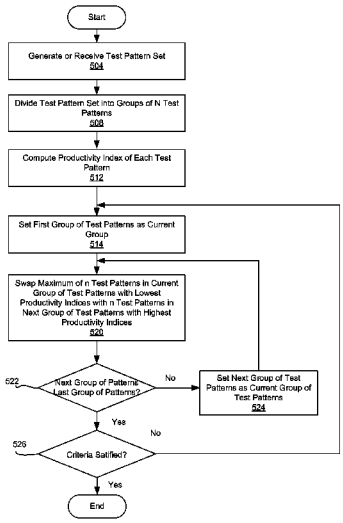
(57) **ABSTRACT**

A method for reordering a test pattern set for testing an integrated circuit is disclosed. A productivity index is computed for each test pattern in a test pattern set. The productivity index of a first test pattern and the productivity index of a second test pattern are compared. If the productivity index of the second test pattern is larger than the productivity index of the first test pattern, the location of the first test pattern and the second test pattern are swapped.

20 Claims, 7 Drawing Sheets